
**Space systems — Space launch
complexes, integration sites and other
facilities — General testing guidelines**

*Systèmes spatiaux — Complexes de lancement spatial, sites
d'intégration et autres installations — Lignes directrices pour les
essais*

iTeh Standards
(<https://standards.iteh.ai>)
Document Preview

[ISO/TR 17400:2021](https://standards.iteh.ai/catalog/standards/iso/77abd6c4-fe30-42d1-ac60-720ccef01718/iso-tr-17400-2021)

<https://standards.iteh.ai/catalog/standards/iso/77abd6c4-fe30-42d1-ac60-720ccef01718/iso-tr-17400-2021>



iTeh Standards
(<https://standards.iteh.ai>)
Document Preview

[ISO/TR 17400:2021](https://standards.iteh.ai/catalog/standards/iso/77abd6c4-fe30-42d1-ac60-720ccef01718/iso-tr-17400-2021)

<https://standards.iteh.ai/catalog/standards/iso/77abd6c4-fe30-42d1-ac60-720ccef01718/iso-tr-17400-2021>



COPYRIGHT PROTECTED DOCUMENT

© ISO 2021

All rights reserved. Unless otherwise specified, or required in the context of its implementation, no part of this publication may be reproduced or utilized otherwise in any form or by any means, electronic or mechanical, including photocopying, or posting on the internet or an intranet, without prior written permission. Permission can be requested from either ISO at the address below or ISO's member body in the country of the requester.

ISO copyright office
CP 401 • Ch. de Blandonnet 8
CH-1214 Vernier, Geneva
Phone: +41 22 749 01 11
Email: copyright@iso.org
Website: www.iso.org

Published in Switzerland

Contents

	Page
Foreword	iv
Introduction	v
1 Scope	1
2 Normative references	1
3 Terms and definitions	1
4 General characteristics	2
5 Testing and acceptance phases and goals for launch pad and integration site	5
5.1 Testing phases.....	5
5.2 Acceptance phases.....	5
5.3 Facility testing and acceptance.....	5
5.4 Main system factory testing.....	5
5.5 Main system field testing.....	6
5.6 Launch pad and integration site end-to-end testing.....	6
6 General characteristics for testing and acceptance	7
6.1 General considerations.....	7
6.2 Test and acceptance procedure.....	7
6.3 Main system factory testing.....	8
6.4 Main system field testing.....	10
6.5 Acceptance of the main system and facility after field test.....	13
6.6 Launch pad and integration site end-to-end testing.....	15
6.7 Launch pad or integration site acceptance after end-to-end testing.....	18
7 Main system and facility modifications	20
Bibliography	23

ISO/TR 17400:2021

<https://standards.iteh.ai/catalog/standards/iso/77abd6c4-fe30-42d1-ac60-720ccef01718/iso-tr-17400-2021>

Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see www.iso.org/patents).

Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT), see www.iso.org/iso/foreword.html.

This document was prepared by Technical Committee ISO/TC 20, *Aircraft and space vehicles*, Subcommittee SC 14, *Space systems and operations*.

This second edition cancels and replaces the first edition (ISO/TR 17400:2003), which has been technically revised.

The main changes compared to the previous edition are as follows:

- in the document all recommendations (“should”) were replaced by other verbs (“is”, “are”), all permissions (“may”) were replaced by “can”;
- the term “main system” was updated;
- [3.1](#), [5.5](#), [6.3.3](#), [6.6.5](#), [6.6.8](#) were specified according to comments and proposals of the subcommittee experts.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

Introduction

The purpose of this document is describing the uniform practices for organizing the tests and promoting verification of all parameters and characteristics of various launch complexes. It is necessary to define the functions and to coordinate the activities of all the test participants, namely, the developers of complexes and systems, the manufacturers of systems and equipment, the organizers of tests, the customer, and others.

This document describes test activities and lists who will be responsible for the testing at launch pad and integration sites for launch vehicle and spacecraft.

iTeh Standards (<https://standards.iteh.ai>) Document Preview

[ISO/TR 17400:2021](https://standards.iteh.ai/catalog/standards/iso/77abd6c4-fe30-42d1-ac60-720ccef01718/iso-tr-17400-2021)

<https://standards.iteh.ai/catalog/standards/iso/77abd6c4-fe30-42d1-ac60-720ccef01718/iso-tr-17400-2021>